# POSTER SESSION

## November 17 (Tuesday) 18:00 – 20:00

**P‒1** **MEIS studies of the formation of high-k gadolinium silicate**
M. Werner, P.R. Chalker, P. Bailey, T.C.Q. Noakes

**P‒2** **MEIS structural study of nanowire growth on vicinal Si(100)**
C. Eames, P. Bailey, T.C.Q. Noakes, M. Reakes, S.P. Tear

**P‒3** **Structure of silicon grown atop a cooled rare earth delta doping layer in Si(111) determined by MEIS**
C. Eames, P. Bailey, T.C.Q. Noakes, M. Reakes, S.P. Tear

**P‒4** **Improved operation characteristics of the CIBA High Resolution RBS facility**
T. Osipowicz, T.K. Chan, B. Ho

**P‒5** **Surface structure of 1-$C_nH_{2n+1}$-3-methylimidazolium bis(trifluoromethanesulfonyl)imide studied by high-resolution RBS**
A. Ohno, H. Hashimoto, K. Nakajima, M. Suzuki, K. Kimura

**P‒6** **Au nano-clusters on HOPG and oxides supports analyzed by high-resolution medium energy ion scattering and photoelectron spectroscopy**
K. Mitsuhara, A. Iwamoto, Y. Kitsudo, H. Matsumoto, A. Visikovskiy, T. Akita, Y. Kido

**P‒7** **Development of a compact system for three-dimensional medium-energy ion scattering**
T. Kobayashi, H. Baba, M. Maehara, S. Shimoda, R. Andrzejewski, S. Ueno, Y. Kuwahara, T. Sato

**P‒8** **Soft X-ray measurements from Si crystal using three-dimensional medium-energy ion scattering**
T. Kobayashi, R. Andrzejewski

**P–9** **Simulations of x-rays induced by medium energy ions**
R. Andrzejewski, V.A. Khodyrev, T. Kobayashi

**P–10** **High resolution depth profiling of absorbed hydrogen in platinum group metal nanocrystals on alumina**
M. Wilde, S. Ohno, K. Fukutani

**P–11** **Depth profiling of oxygen in transition metal nitride and carbide thin films by resonant elastic scattering**
Y. Gotoh, Y. Kawashima, R. Fujii, H. Tsuji

**P–12** **Analysis of corrosion layer of carbon steel by using simultaneous micro-PIXE/RBS system**
S. Matsuyama, K. Ishii, H. Yamazaki, M. Fujiwara, Y. Kikuchi, M. Nakhostin, Y. Kawamura, S. Tsuboi, K. Yamanaka, M. Watanabe, S. Ohkura, Y. Hashimoto, M. Fujikawa, G. Catella, K. Fujiki, Y. Hatori, N. Hamada, S. Tanino

**P–13** **RBS/PIXE analysis of electric field-assisted copper diffusion into glass**
F. Qiu, T. Narusawa, F. Nishiyama

**P–14** **Elemental depth profiles of Au/(Pt)/Ti films grown on diamond (001) surface studied by Rutherford backscattering spectroscopy**
Y. Hoshino, Y. Saito, J. Nakata

**P–15** **TOF-ERDA for the analysis of light elements using a MeV He beam**
K. Yasuda, C. Batchuluun, R. Ishigami, S. Hibi

**P–16** **Information depth in LEIS**
D. Primetzhofer, M. Spitz, S.N: Markin, P. Bauer

**P–17** **Study of the elemental distribution in high-κ/ metal gate stacks**
F. Pierre, M. Py, J.P. Barnes, S Lhostis, M. Gros-Jean, C. Gaumer

**P–18** **Combined study of low dose ultra shallow Arsenic implants in Si by MEIS and Extremely Low Energy SIMS**
M. Py, F. Pierre, J.P Barnes, M. Juhel

**P‒19** **Assessment of SIMS quantification in the first few nm for B, P and As ultra shallow implants**
A. Merkulov, P. Peres, J. Choi, M. Schuhmacher, H.-U. Ehrke, N. Loibl

**P‒20** **Chemical state resolved depth-profiling using synchrotron XPS and the maximum entropy method**
J.R. Harries, M. Tode, K. Inoue, Y. Sumimoto, A. Yoshigoe, Y. Teraoka

**P‒21** **Three dimensional characterization in a real device by Atom Probe Tomography**
K. Kitamoto, J. Kato, T. Miyagi, H. Hashimoto, K. Inoue, T. Toyama, H. Takamizawa, Y. Nagai, A. Karen

**P‒22** **Surface structure modification after slow ion irradiation**
B. Ban d'Etat, I. Alzaher, S. Akcöltekin, A. Macé, B. Manil, H. Rothard, M. Schleberger, H. Lebius

**P‒23** **Discharge property and surface structure of MgO thin film for plasma display panels**
L.Y. Chen, Y. Tanaka, A. Ide-Ektessabi

**P‒24** **Defect formation process caused by molecular beams into diamond**
S.T. Nakagawa, H. Kanda, G. Betz

**P‒25** **The electronic stopping force of a crystal for a cluster beam impact using molecular dynamic simulation**
S.T. Nakagawa

**P‒26** **Investigation of cluster ion irradiation damage with HR-RBS**
T. Seki, T. Aoki, J. Matsuo

**P‒27** **In situ measurement of surface potential induced on MgO thin film surface under ion irradiation using ion scattering spectroscopy**
T. Nagatomi, T. Kuwayama, K. Yoshino, Y. Morita, M. Nishitani, M. Kitagawa, Y. Takai

**P‒28** **Release of light elements from polyethylene naphthalate foils during MeV proton beam irradiation: Effect of Al deposition on foils**
M. Saito, F. Nishiyama, K. Takahiro

**P‒29** **Sub-linear effect in kinetic secondary electron emission induced by MeV/atom carbon cluster bombardment**
T. Kaneko , H. Kudo, S. Tomita

**P‒30** **Effect of residual oxygen impurity on $Si^+$ and $Si^{2+}$ yields sputtered from a clean Si(111) surface**
Y. Sakuma, M. Kato, S. Yagi, K. Soda

**P‒31** **Transmission of ions through a tapered-glass capillary: imaging the dynamics of the charging-up process**
A. Cassimi, H. Lebius, P. Rousseau, T. Muranaka, B.A. Huber, D. Lelievre, J.M. Ramillon, T. Been, T. Ikeda, Y. Kanai, T.M. Kojima, Y. Iwai, Y. Yamazaki, H. Khemliche, N. Bundaleski, P. Roncin

**P‒32** **A novel micro-irradiation facility for biological targets**
W. Meissl, Y. Iwai, K. Maeshima, T. Ikeda, T.M. Kojima, Y. Kanai

**P‒33** **Modification of the surface morphology and electrical properties of Pd film by low energy $Ar^+$ irradiation**
M. Zhao, A. Inouye, S. Yamamoto, M. Yoshikawa, S. Nagata, T. Shikama

**P‒34** **Modification of $TiO_2$ thin films during ERD analysis with MeV heavy ions**
J. Jensen, L. Hultman, A. Surpi, T. Kubart

**P‒35** **Fabrication and assessment of metal capillaries for ion beam focusing**
Y. Kitaoka, K. Ishikawa, T. Narusawa, K. Fukutani

**P‒36** **Structure and dynamics of the NiAl(110) surface studied by high-resolution ion scattering combined with density functional calculations**
T. Kogita, M. Kohyama, T. Nishimura, Y. Kido